

OptiMOS[™]-5 Power-Transistor





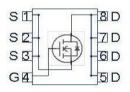
Product Summary

V_{DS}	100	V
$R_{\mathrm{DS(on),max}}$	42	mΩ
I _D	18	Α

Features

- OptiMOS™ power MOSFET for automotive applications
- N-channel Enhancement mode Logic Level
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested
- Feasible for automatic optical inspection (AOI)

PG-TSDSON-8	3
1 College	



Туре	Package	Marking
IAUZ18N10S5L420	PG-TSDSON-8	5N1L420

Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _C =25°C, V _{GS} =10V	18	А
		$T_{\rm C}$ =100°C, $V_{\rm GS}$ =10 $V^{1)}$	13	
Pulsed drain current ¹⁾	I _{D,pulse}	T _C =25°C	72	
Avalanche energy, single pulse ¹⁾	E _{AS}	I _D =7A	11	mJ
Avalanche current, single pulse	I _{AS}	-	7	А
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P_{tot}	T _C =25°C T _J =175°C	30	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	_



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ¹⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	5.0	K/W
Thermal resistance, junction - ambient	R_{thJA}	6 cm ² cooling area ²⁾	-	-	62	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	$V_{\rm GS}$ =0V, $I_{\rm D}$ = 1mA	100	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=8\mu{\rm A}$	1.2	1.7	2.2	7
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =100V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C	-	-	1	μΑ
		$V_{\rm DS}$ =100V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ¹⁾	-	-	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20V, V _{DS} =0V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =4.5V, I _D =9A	-	46	55	mΩ
		V _{GS} =10V, I _D =9A	-	34.5	42	
Gate resistance ¹⁾	R_{G}		-	1.8	-	Ω



Parameter	Symbol Conditions	Values			Unit	
			min.	typ.	max.	
Dynamic characteristics ¹⁾						
Input capacitance	Ciss		-	356	470	pF
Output capacitance	Coss	V_{GS} =0V, V_{DS} =50V, f=1MHz	-	68	88	1
Reverse transfer capacitance	C _{rss}		-	6	9	
Turn-on delay time	$t_{d(on)}$		-	1	-	ns
Rise time	t _r	V _{DD} =50V, V _{GS} =10V,	-	1	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =18A, $R_{\rm G}$ =3.5 Ω	-	3	-	
Fall time	t_{f}		-	3	-	
Gate Charge Characteristics ¹⁾	ı		T	Г	T	
Gate to source charge	Q _{gs}		-	1.2	1.7	nC
Gate to drain charge	Q_{gd}	$V_{\rm DD}$ =50V, $I_{\rm D}$ =9A, $V_{\rm GS}$ =0 to 10V	-	1.2	2.0	
Gate charge total	Qg		-	5.4	8	
Gate plateau voltage	V _{plateau}		-	3.3	-	V
Reverse Diode						
Diode continous forward current ¹⁾	Is	T -25°C	-	-	18	А
Diode pulse current	I _{S,pulse}	- T _C =25°C	-	-	72	
Diode forward voltage	V_{SD}	V _{GS} =0V, I _F =9A, T _j =25°C	-	0.9	1.1	V
Reverse recovery time ¹⁾	t _{rr}	V_{R} =50V, I_{F} =18A, di_{F}/dt =100A/ μ s	-	36	-	ns
Reverse recovery charge ¹⁾	Q _{rr}		-	33	-	nC

¹⁾ Specified by design. Not subject to production test.

 $^{^{2)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.

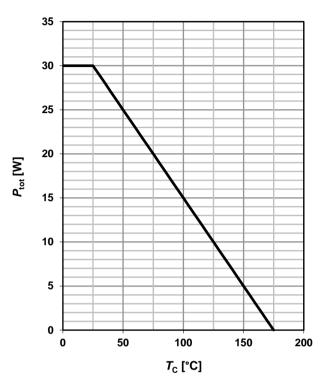


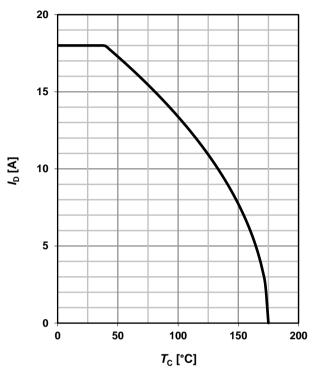
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}$$





3 Safe operating area

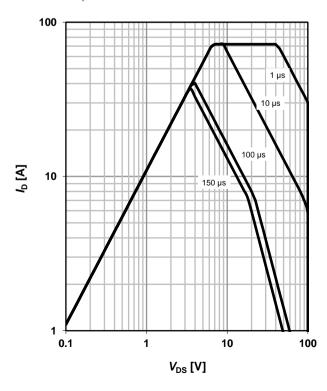
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

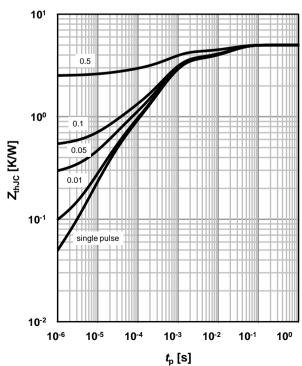
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_{p})$$

parameter: $D=t_p/T$



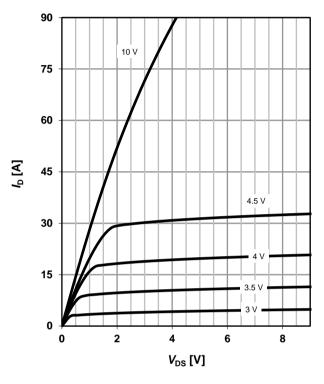




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_i = 25 \text{ °C}$

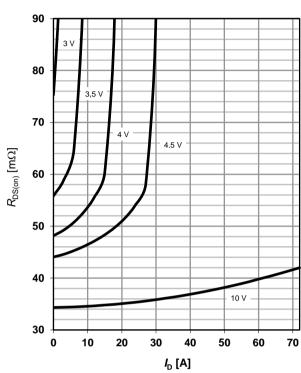
parameter: V_{GS}



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}$

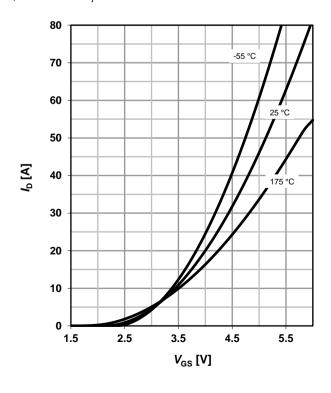
parameter: V_{GS}



7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6V$

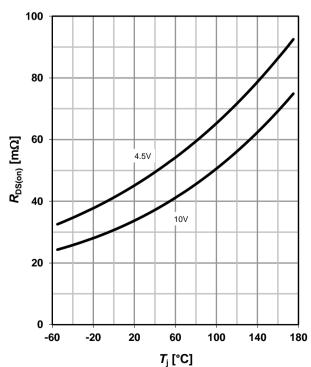
parameter: $T_{\rm j}$



8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_j); I_D = 9 A$

Parameter: V_{GS}





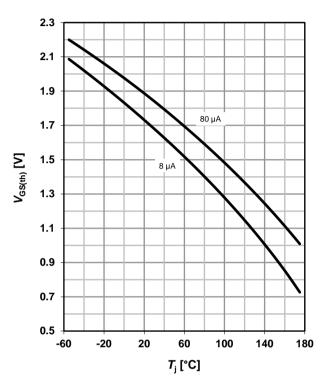
9 Typ. gate threshold voltage

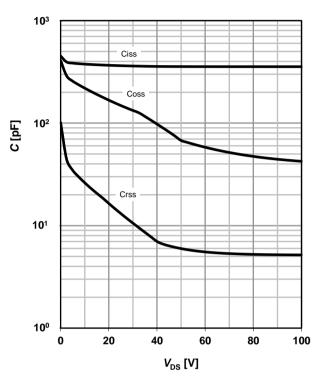
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristics

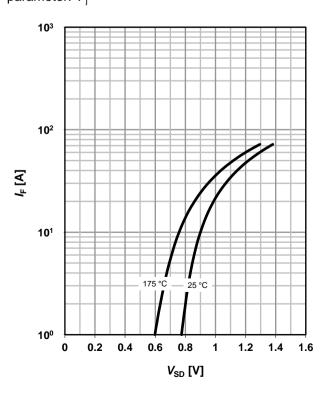
 $IF = f(V_{SD})$

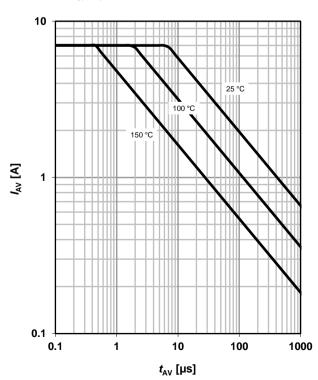
parameter: $T_{\rm j}$

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{i(start)}







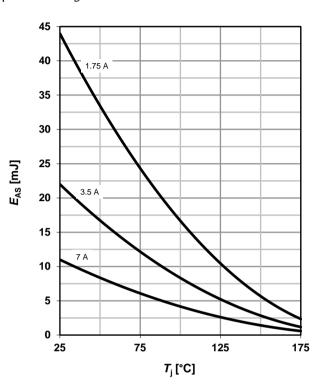
13 Avalanche energy

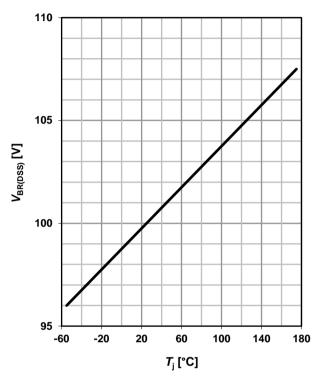
$E_{AS} = f(T_i)$

parameter: I_D

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_i); I_D = 1 \text{ mA}$$

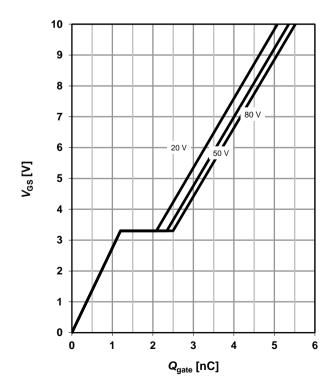




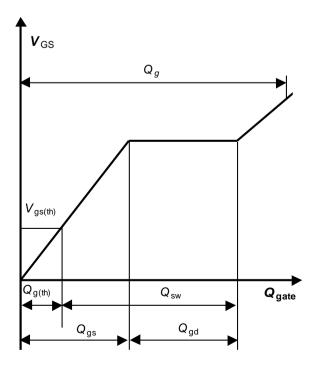
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 9 A pulsed$

parameter: V_{DD}

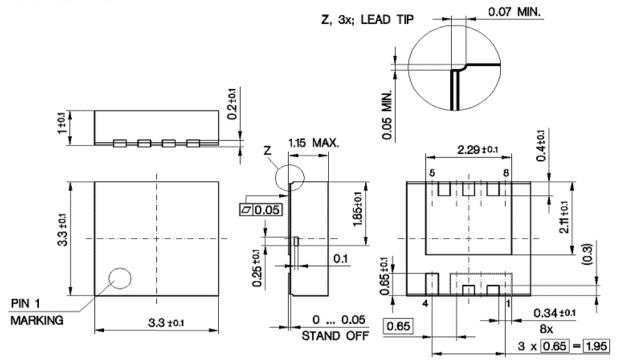


16 Gate charge waveforms

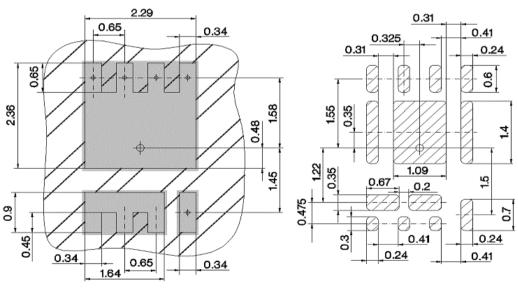




PG-TSDSON-8: Outline



Footprint



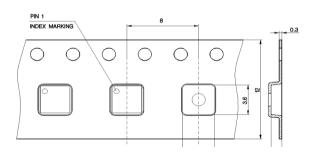


Solder Mask

Stencil Apertures

Dimensions in mm

Packaging





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Revision History

Version	Date	Changes		
Revision 1.0	23.07.2019	Final Data Sheet		